捷多邦,专业PCB**SN54EV.T24650加启SN5**4LVT16501 3.3-V ABT 18-BIT UNIVERSAL BUS TRANSCEIVERS WITH 3-STATE OUTPUTS

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- State-of-the-Art Advanced BiCMOS Technology (ABT) Design for 3.3-V Operation and Low-Static Power Dissipation
- Members of the Texas Instruments Widebus™ Family
- Support Mixed-Mode Signal Operation (5-V Input and Output Voltages With 3.3-V V_{CC})
- Support Unregulated Battery Operation Down to 2.7 V
- UBT™ (Universal Bus Transceiver)
 Combines D-Type Latches and D-Type
 Flip-Flops for Operation in Transparent,
 Latched, or Clocked Mode
- Typical V_{OLP} (Output Ground Bounce)
 < 0.8 V at V_{CC} = 3.3 V, T_A = 25°C
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 500 mA
 Per JEDEC Standard JESD-17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Support Live Insertion
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- Flow-Through Architecture Optimizes
 PCB Layout
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

SN54LVT16501 . . . WD PACKAGE SN74LVT16501 . . . DGG OR DL PACKAGE (TOP VIEW)

OEAB [1	56	GND
LEAB [2	55	CLKAB
A1 [3	54	B1
GND [4	53	GND
A2 [5	52	B2
A3 [6		B3
V _{CC} [7	50] v _{cc}
A4 [B4
A5 [9	48	B5
A6 [10	47] B6
GND [11		GND
A7 [B7
A8 [13		B8
A9 [14		B9
A10 [15		B10
A11 [16	41	B11
A12 [17	40	B12
GND [18		GND
A13 [19	38	B13
A14 [20	37	B14
A15 [21		B15
v _{cc} [22	35] V _{CC}
A16 [23	34	B16
A17 [24	33	B17
GND [25	32	GND
A18 [26		B18
OEBA [27	30	CLKBA
LEBA [28	29] GND

description

The 'LVT16501 are 18-bit universal bus transceivers designed for low-voltage (3.3-V) V_{CC} operation, but with the capability to provide a TTL interface to a 5-V system environment.

Data flow in each direction is controlled by output-enable (OEAB and OEBA), latch-enable (LEAB and LEBA), and clock (CLKAB and CLKBA) inputs. For A-to-B data flow, the devices operate in the transparent mode when LEAB is high. When LEAB is low, the A data is latched if CLKAB is held at a high or low logic level. If LEAB is low, the A-bus data is stored in the latch/flip-flop on the low-to-high transition of CLKAB. When OEAB is high, the outputs are active. When OEAB is low, the outputs are in the high-impedance state.

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description (continued)

Data flow for B to A is similar to that of A to B but uses OEBA, LEBA, and CLKBA. The output enables are complementary (OEAB is active high and OEBA is active low).

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

To ensure the high-impedance state during power up or power down, $\overline{\text{OE}}$ should be tied to V_{CC} through a pullup resistor. The minimum value of the resistor is determined by the current-sinking capability of the driver. OE should be tied to GND through a pulldown resistor; the minimum value of the resistor is determined by the current-sourcing capability of the driver.

The SN74LVT16501 is available in TI's shrink small-outline (DL) and thin shrink small-outline (DGG) packages, which provide twice the input/output (I/O) pin count and functionality of standard small-outline packages in the same printed circuit board area.

The SN54LVT16501 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74LVT16501 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE†

	INPUTS							
OEAB	LEAB	CLKAB	Α	В				
L	Х	Х	Х	Z				
Н	Н	Χ	L	L				
Н	Н	Χ	Н	Н				
Н	L	\uparrow	L	L				
Н	L	\uparrow	Н	Н				
Н	L	Н	Χ	в ₀ ‡				
Н	L	L	Χ	в ₀ ‡ в ₀ §				

[†] A-to-B data flow is shown; B-to-A flow is similar but uses OEBA, LEBA, and CLKBA.

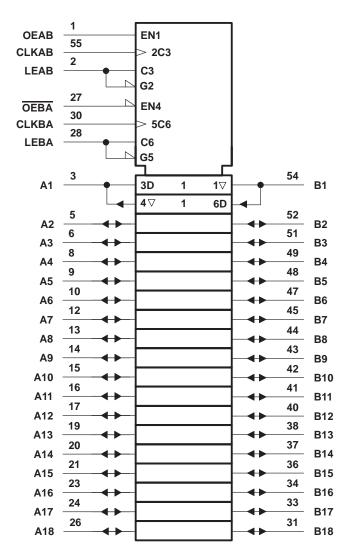


[‡]Output level before the indicated steady-state input conditions were established, provided that CLKAB was high before LEAB went low

[§] Output level before the indicated steady-state input conditions were established

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logic symbol†

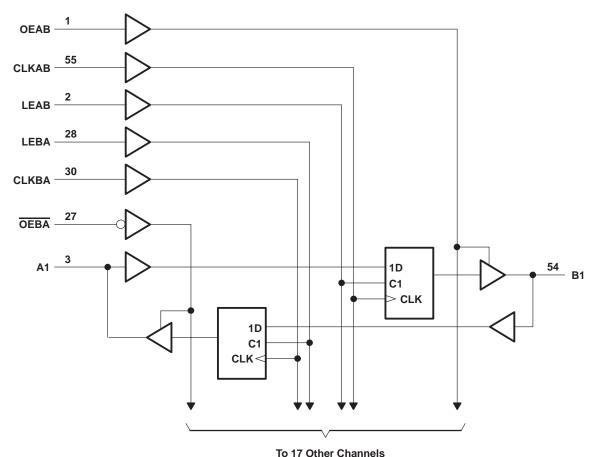


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC} –0.5 V to 4.6 V
Input voltage range, V _I (see Note 1)
Voltage range applied to any output in the high state or power-off state, V _O (see Note 1)0.5 V to 7 V
Current into any output in the low state, I _O : SN54LVT16501
SN74LVT16501 128 mA
Current into any output in the high state, I _O (see Note 2): SN54LVT16501
SN74LVT16501 64 mA
Input clamp current, I_{IK} ($V_I < 0$)
Output clamp current, I _{OK} (V _O < 0)
Maximum power dissipation at T _A = 55°C (in still air) (see Note 3): DGG package
DL package
Storage temperature range, T _{stq} –65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 - 2. This current flows only when the output is in the high state and $V_O > V_{CC}$.
 - 3. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the *Package Thermal Considerations* application note in the *ABT Advanced BiCMOS Technology Data Book*.



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recommended operating conditions (see Note 4)

		SN54LV	T16501	SN74LV	UNIT		
			MIN	MAX	MIN	MAX	UNIT
Vcc	Supply voltage	2.7	3.6	2.7	3.6	V	
VIH	High-level input voltage	2		2		V	
V _{IL}	Low-level input voltage		0.8		0.8	V	
٧ _I	Input voltage		5.5		5.5	V	
IOH	High-level output current			-24		-32	mA
loL	Low-level output current		48		64	mA	
Δt/Δν	Input transition rise or fall rate	Outputs enabled		10		10	ns/V
TA	Operating free-air temperature		-55	125	-40	85	°C

NOTE 4: Unused control inputs must be held high or low to prevent them from floating.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST	CONDITIO	Me	SN5	4LVT16	501	SN7	4LVT16	501	UNIT	
PAI	RAWETER	TEST	CONDITIC)NS	MIN	TYP†	MAX	MIN	TYP†	MAX	UNIT	
٧ _{IK}		$V_{CC} = 2.7 \text{ V},$	I _I = -18 ı	mA			-1.2			-1.2	V	
VOH		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V},$	I _{OH} = -1	Ι00 μΑ	V _{CC} -0.2			V _{CC} -0.2				
		$V_{CC} = 2.7 \text{ V},$	I _{OH} = -8	3 mA	2.4	2.4		2.4			V	
		VCC = 3 V	$I_{OH} = -2$	24 mA	2						V	
		VCC = 3 V	I _{OH} = -3	32 mA				2				
		V _{CC} = 2.7 V	I _{OL} = 10	0 μΑ			0.2			0.2		
		VCC = 2.7 V	I _{OL} = 24	· mA			0.5			0.5		
\ _{\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\}			I _{OL} = 16	mA			0.4			0.4	V	
VOL		VCC = 3 V	I _{OL} = 32	mA			0.5			0.5	v	
		ACC = 2 A	I _{OL} = 48	mA			0.55					
			I _{OL} = 64	· mA						0.55]	
	Control pins	$V_{CC} = 3.6 \text{ V},$		or GND			±1			±1		
	Control pins	$V_{CC} = 0 \text{ or } 3.6 \text{ V},$	V _I = 5.5 V		10			10			1	
l _l	A or B ports‡	V _{CC} = 3.6 V	$V_{ } = 5.5$	V	120		20		20	μΑ		
			$V_I = V_{CC}$				1			1		
			V _I = 0				- 5			– 5		
I _{off}		$V_{CC} = 0$,	V_I or V_O	= 0 to 4.5 V						±100	μΑ	
lia in	A or B ports	V _C C = 3 V		V _I = 0.8 V				75			μА	
II(hold)	A of B ports	VCC = 3 V	V _I = 2 V		-75			- 75			μΑ	
I _{OZH}		$V_{CC} = 3.6 \text{ V},$	V _O = 3 \	/						1	μΑ	
l _{OZL}		$V_{CC} = 3.6 \text{ V},$	$V_0 = 0.5$	5 V						-1	μΑ	
				Outputs high			0.12			0.12		
Icc		$V_{CC} = 3.6 \text{ V},$ $V_{I} = V_{CC} \text{ or GND}$	$I_O = 0$,	Outputs low			5			5	mA	
		1 - 1 - 1 O O O O O O		Outputs disabled			0.12			0.12		
ΔICC§	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}, \text{One input at } V_{CC} - 0.6 \text{ V},$ Other inputs at V_{CC} or GND				0.2			0.2	mA			
Ci		V _I = 3 V or 0				3.5			3.5		pF	
C _{io}		V _O = 3 V or 0				12			12		pF	



[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.
‡ Unused pins at V_{CC} or GND
§ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

				SN54LVT16501				SN74LVT16501				
			$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V} $ $V_{CC} = 2.7 \text{ V}$		V _{CC} = 3.3 V ± 0.3 V		V _{CC} = 2.7 V		UNIT			
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
fclock	f _{clock} Clock frequency		0	150	0	125	0	150	0	125	MHz	
	Pulse duration	LE high	3.3		3.3		3.3		3.3		ns	
t _W	Fuise duration	CLK high or low	3.3		3.3		3.3		3.3			
		A before CLKAB↑	1.6		2.1		1.6		2.1		ns	
	Catum times	B before CLKBA↑	1.6		2.1		1.6		2.1			
t _{su}	Setup time	A or B before LE↓, CLK high	3.1		2.7		2.6		1.9			
		A or B before LE↓, CLK low	2.6		2.0		2		1.3			
.	Hold time	A or B after CLK↑	2		2.1		2		2.1		ns	
^t h	i ioid tiitle	A or B after LE↓	1.3		1.2		0.9		1.2		115	

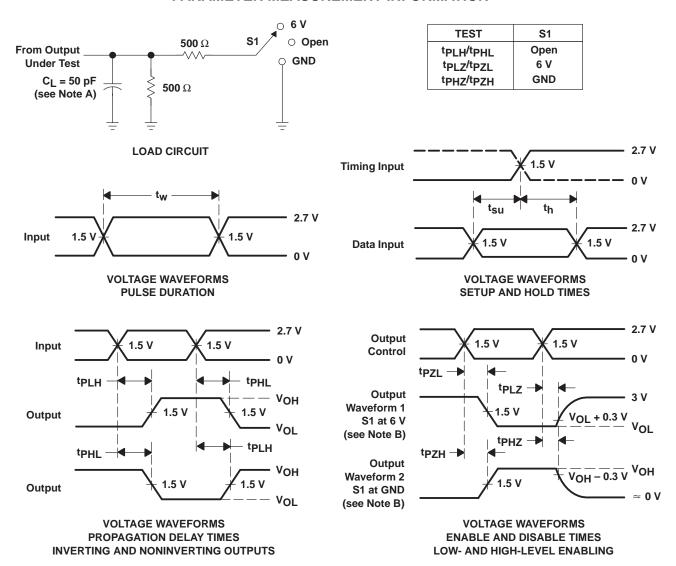
switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

			SN54LVT16501									
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 3.3 V ± 0.3 V		V _{CC} = 2.7 V		VCC = 3.3 V ± 0.3 V			V _{CC} = 2.7 V		UNIT
			MIN	MAX	MIN	MAX	MIN	TYP [†]	MAX	MIN	MAX	
fmax			150		125		150			125		MHz
t _{PLH}	D or A	A or B	1.7	5.4		6.8	1.7	3	5.4		6.8	ns
t _{PHL}	B or A	AOIB	1.6	6		7.8	1.6	3.2	5.9		7.7	115
t _{PLH}	LEBA or LEAB	A or B	2.3	7.3		9	2.3	4	7		8.5	ns
^t PHL	LEBA UI LEAD	AUD	2.7	8.2		9.8	2.7	4.3	7.9		9.7	115
t _{PLH}	CLKBA or	A or B	2.5	8.3		9.7	2.5	4.1	7.9		9.2	ns
t _{PHL}	CLKAB	AOIB	3.5	9.4		10.7	3.5	5.4	8.9		10.4	115
^t PZH	OEBA or OEAB	A or B	1.2	5.1		6.1	1.2	3	5		5.9	ns
tPZL	OEDA OF OEAB	AOIR	1.5	5.9		7	1.5	3	5.8		6.9	115
t _{PHZ}	OEBA or OEAB	A or B	2.7	7.5		8.5	2.7	4.6	7.4		8.3	ns
tPLZ	OLDA OI OEAB	AUID	2.8	6.8		7.5	2.8	4.7	6.7		7.2	115

 $[\]dagger$ All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

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PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \,\Omega$, $t_f \leq 2.5 \,$ ns, $t_f \leq 2.5 \,$ ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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